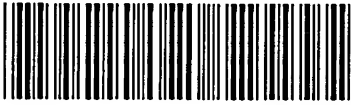


Search Notes

Application/Control No.

10/523,788

Examiner

Jacob Y. Choi

Applicant(s)/Patent under
Reexamination

ITOU, DAISUKE

Art Unit

2875

SEARCHED

Class	Subclass	Date	Examiner
362	614, 632, 634, 561, 600, 606	11/2/2006	JC
362	609, 615	11/2/2006	JC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass & Text Search Conducted by Examiner	11/2/2006	JC